Notice of References Cited Application/Control No. 10/595,439 Applicant(s)/Patent Under Reexamination WOON ET AL. Examiner CATHERINE THIAW Applicant(s)/Patent Under Reexamination WOON ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,960,214	09-1999	Sharpe et al.	710/15
*	В	US-2001/0039587	11-2001	UHLER et al.	709/229
*	C	US-5,724,512	03-1998	Winterbottom, Philip Steven	709/226
*	D	US-7,293,067	11-2007	Maki et al.	709/217
*	Е	US-2005/0149468	07-2005	Abraham, Raji	707/001
*	F	US-2004/0172466	09-2004	Douglas et al.	709/224
*	G	US-2004/0083210	04-2004	Ochiai et al.	707/003
*	Η	US-7,099,937	08-2006	Ochiai et al.	709/224
*	I	US-6,374,293	04-2002	Dev et al.	709/220
*	J	US-6,216,168	04-2001	Dev et al.	709/245
*	K	US-6,519,626	02-2003	Soderberg et al.	709/203
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
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	R					
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	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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	х						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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